



■ 主要用途

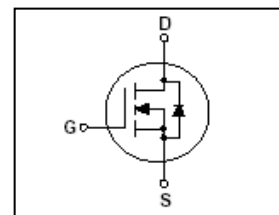
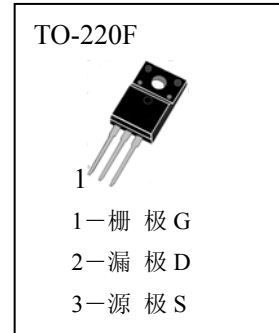
高速开关应用。

■ 极限值 (T_a=25°C)

- T_{stg}——贮存温度..... -55~150°C
- T_j——结温..... 150°C
- V_{DSS}——漏极—源极电压..... 600V
- V_{GS}——栅极—源极电压..... ±30V
- I_D——漏极电流 (T_c=25°C) 7.5A
- P_D——耗散功率 (T_c=25°C) 48W

■ 电参数 (T_a=25°C)

■ 外形图及引脚排列



参数符号	符号说明	最小值	典型值	最大值	单位	测试条件
BV _{DSS}	漏—源极击穿电压	600			V	I _D =250 μ A, V _{GS} =0V
I _{DSS}	零栅压漏极电流			1	μ A	V _{DS} = 600V, V _{GS} =0
I _{GSS}	栅极泄漏电流			± 100	nA	V _{GS} =± 30V, V _{DS} = 0V
V _{GS(th)}	栅—源极开启电压	2.0		4.0	V	V _{DS} = V _{GS} , I _D = 250 μ A
R _{DS(on)}	漏—源极导通电阻		1.0	1.2	Ω	V _{GS} =10V, I _D = 3.75A
g _{fs}	正向跨导		8.7		S	V _{DS} = 40V, I _D =3.75A *
C _{iss}	输入电容		965	1255	pF	V _{DS} = 25V, V _{GS} =0, f=1MHz
C _{oss}	输出电容		105	135	pF	
C _{rss}	反向传输电容		12	16	pF	
t _{d(on)}	导通延迟时间		16.5	45	nS	V _{DD} = 300V, I _D = 7.5A (峰值) R _G = 25 Ω
t _r	上升时间		60.5	130	nS	
t _{d(off)}	断开延迟时间		81	170	nS	
t _f	下降时间		64.5	140	nS	*
Q _g	栅极总电荷		28	36	nC	V _{DS} = 480V V _{GS} =10V I _D =7.5A *
Q _{gs}	栅极—源极电荷		4.5		nC	
Q _{gd}	栅极—漏极电荷		12		nC	
I _s	源极—漏极二极管正向电流			7.5	A	
V _{SD}	源极—漏极二极管导通电压			1.4	V	I _S = 7.5A, V _{GS} =0
R _{th(j-c)}	热阻			2.6	°C/W	结到外壳

*注：脉冲测试，宽度≤300 μ S, 占空比≤2%



特性曲线

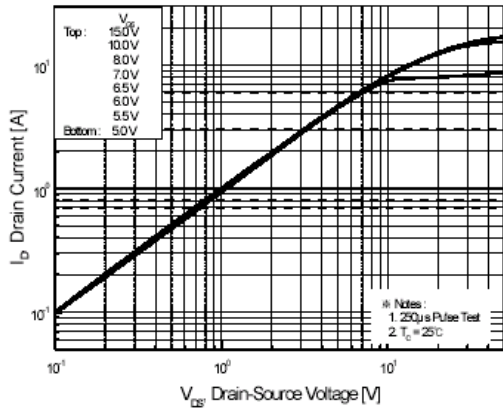


Figure 1. On-Region Characteristics

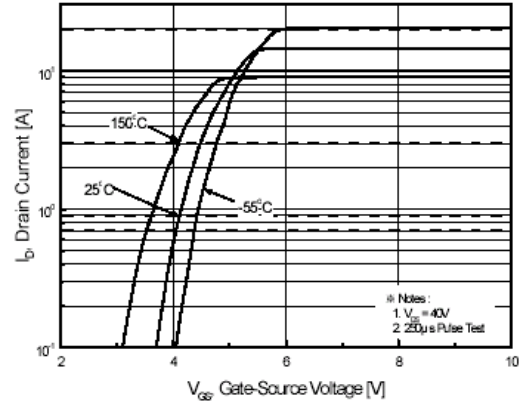


Figure 2. Transfer Characteristics

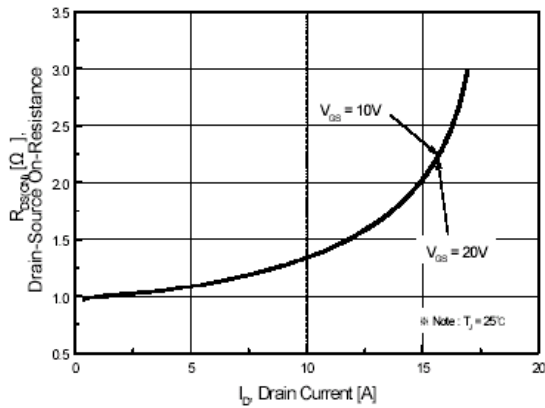


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

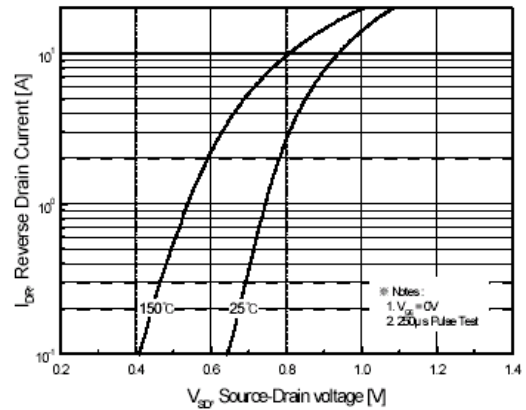


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

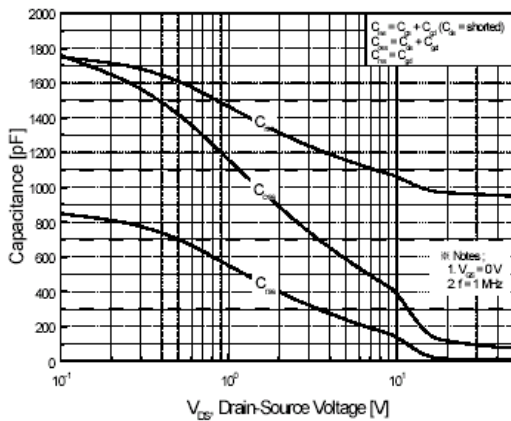


Figure 5. Capacitance Characteristics

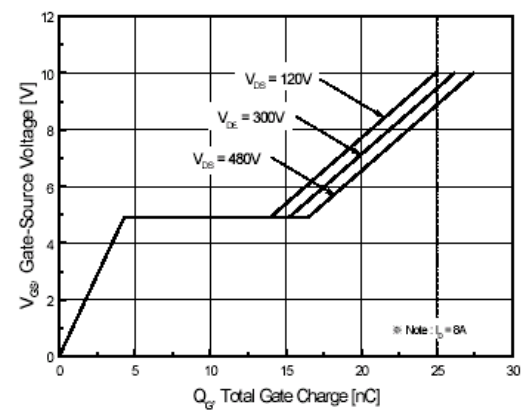


Figure 6. Gate Charge Characteristics



■ 特性曲线

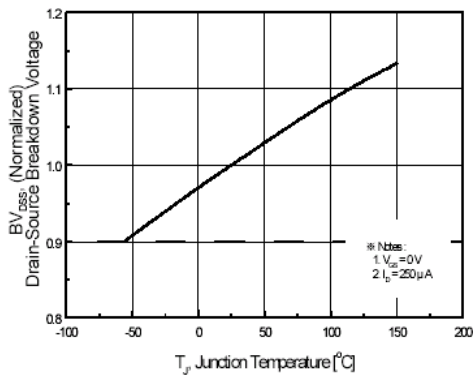


Figure 7. Breakdown Voltage Variation vs Temperature

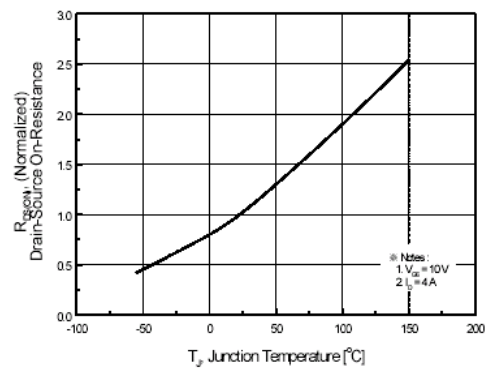


Figure 8. On-Resistance Variation vs Temperature

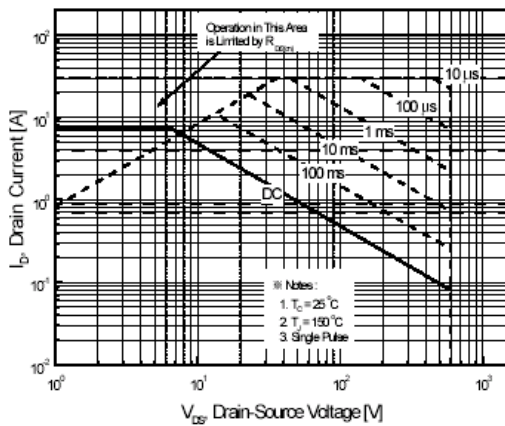


Figure 9 Maximum Safe Operating Area for HFF8N60

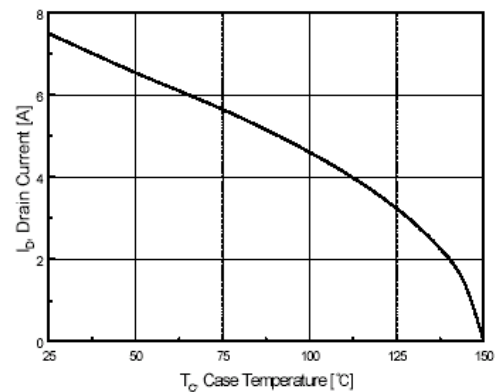


Figure 10. Maximum Drain Current vs Case Temperature

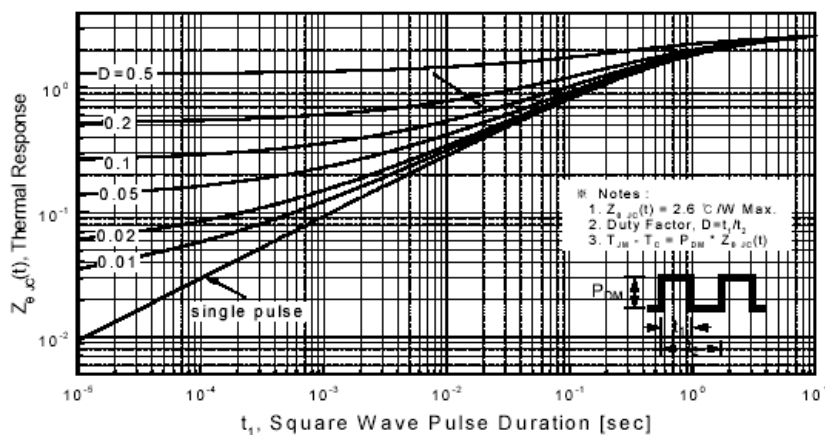
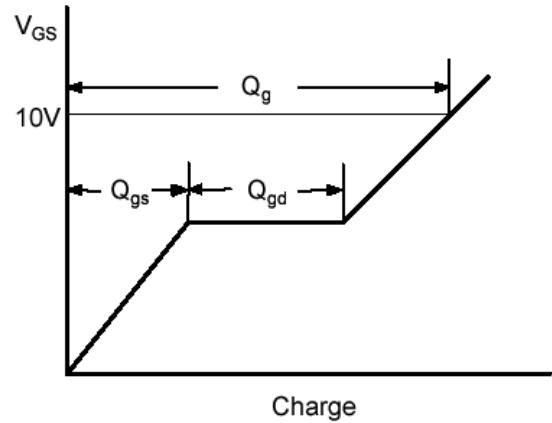
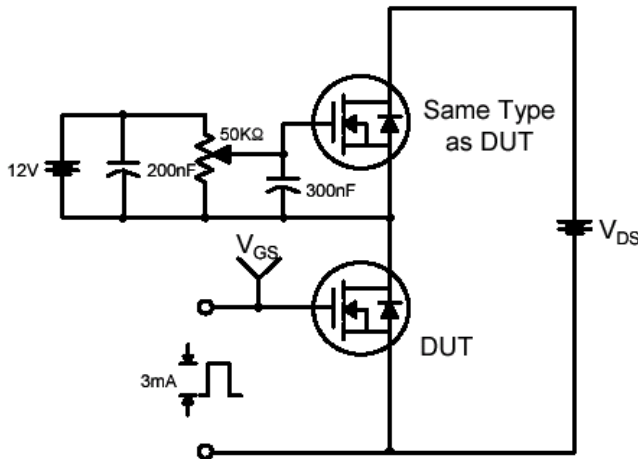


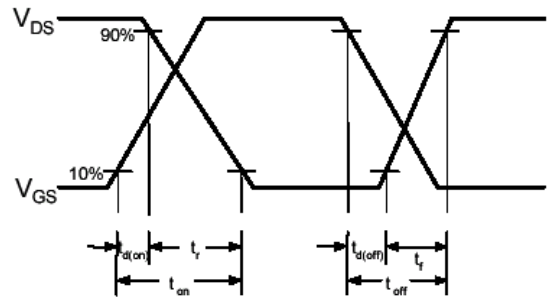
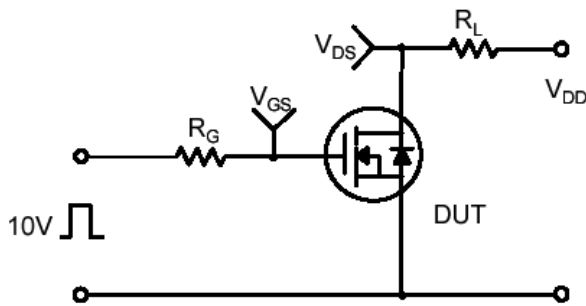
Figure 11-2. Transient Thermal Response Curve for HFF8N60



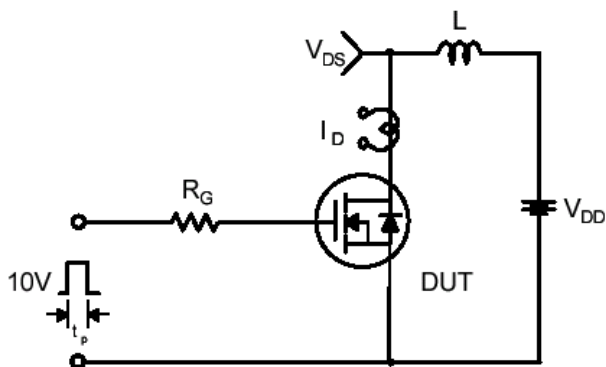
Gate Charge Test Circuit & Waveform



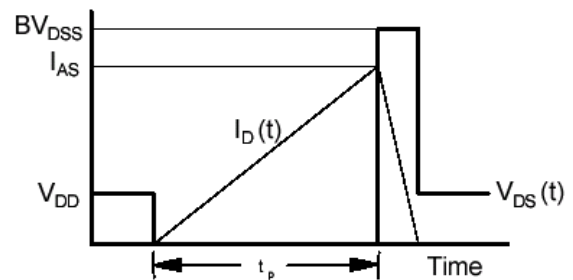
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching Test Circuit & Waveforms



$$E_{AS} = \frac{1}{2} L I_{AS}^2 \frac{BV_{DSS}}{BV_{DSS} - V_{DD}}$$





Peak Diode Recovery dv/dt Test Circuit & Waveforms

